

## TEST REPORT IEC 62471 Photobiological safety of lamps and lamp systems

Total number of pages .....:

Testing Laboratory...... SAMSUNG ELECTRONICS Co., Ltd.

Applicant's name ...... SAMSUNG ELECTRONICS Co., Ltd.

Korea

Test specification:

Standard.....: IEC 62471:2006 (First Edition)

Test procedure ......: N/A
Non-standard test method .....: N/A

Test Report Form No. ..... IEC62471A

TRF Originator ...... VDE Testing and Certification Institute

Master TRF ...... Dated 2009-05

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Test item description ...... LED PKG (LM283B+)

Trade Mark.....: SAMSUNG

Manufacturer ...... Same as Testing Laboratory

Model/Type reference ...... SPMWH\*229AQ\*\*\*\*\*\*\*

(Tested sample: SPMWH1229AQ5SGPMSB)

Ratings ...... DC 110 mA / 9,28 V

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Testing procedure and testing location:							
	Testing Laboratory:	SAMSUNG ELECTRONICS Co., Ltd. (LED Biz.)					
Testing location/ address:		1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do, 17113 Korea					
	Associated Laboratory:						
Testing location/ address:							
	Tested by (name + signature):						
	Approved by (+ signature):						
	Testing procedure: TMP						
	Tested by (name + signature):						
	Approved by (+ signature):						
Testing location/ address:							
	Testing procedure: WMT						
	Tested by (name + signature):						
	Witnessed by (+ signature):						
	Approved by (+ signature):						
Testing location/ address:							
	Testing procedure: SMT						
	Tested by (name + signature):						
	Approved by (+ signature):						
	Supervised by (+ signature):						
Testing location/ address::							
	Testing procedure: RMT						
	Tested by (name + signature):						
	Approved by (+ signature):						
	Supervised by (+ signature):						
Test	ing location/ address:						

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Summary of testing:									
Tests performed (name of test and test clause):	Testing location:								
<ul> <li>The sample was applied DC 110 mA following by applicant request.</li> <li>The sample was measured at 25°C.</li> </ul>	SAMSUNG ELECTRONICS Co., Ltd 1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do, 17113, Korea								
Summary of compliance with National Differences:									
The sample(s) tested complies with the requirements of IEC 62471:2006 and EN 62471:2008.  See Attachment at the end of this report for compliance with European Group Difference and National Differences.									
Copy of marking plate:									

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Те	st item particulars:							
Tested lamp					sed lamps			
Те	sted lamp system:							
Lamp classification group (IEC):			☐ risk 1	☐ risk 2	☐ risk 3			
Lamp classification group (EN)		☐ exempt	⊠ risk 1	☐ risk 2	☐ risk 3			
Lamp cap								
Bulb:								
Rated of the lamp:		See Page 1						
Furthermore marking on the lamp:								
Se	asoning of lamps according IEC standard:							
Us	ed measurement instrument:							
Temperature by measurement:		24.0 - 25.0 °C						
Inf	ormation for safety use:	Not required						
Po	ssible test case verdicts:							
_	test case does not apply to the test object:	N/A						
_	test object does meet the requirement:	P (Pass)						
ı	test object does not meet the requirement:	F (Fail)						
Те	sting:							
Date of receipt of test item		2018-01-17						
Date (s) of performance of tests:		2018-01-26~2018-01-30						
Ge	eneral remarks:							
The test results presented in this report relate only to the object tested.  This report shall not be reproduced, except in full, without the written approval of the Issuing testing laboratory.  "(See Enclosure #)" refers to additional information appended to the report.  "(See appended table)" refers to a table appended to the report.  Throughout this report a comma (point) is used as the decimal separator.  List of test equipment must be kept on file and available for review.								
Ge	eneral product information:							
	- PKG: LM283B+ - CCT: 6500K - CRI: 80 - Flux rank: SB - Tested current: DC 110 mA - A photo of test sample.							
Th	Throughout this report a 🖂 comma / 🗌 point is used as the decimal separator.							